

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination
		09/973,302	CHAIKO, DAVID J.
Examiner	Art Unit		
Katarzyna Wyrozebski Lee	1714		Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,555,610	04-2003	Blanton et al.	524/445
B	US-6,172,121	01-2001	Chaiko	516/101
C	US-6,521,678	02-2003	Chaiko	523/333
D	US-5,552,469	09-1996	Beall et al.	524/445
E	US-6,034,163	03-2000	Barbee et al.	524/445
F	US-6,403,231	06-2002	Mueller et al.	428/474.4
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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